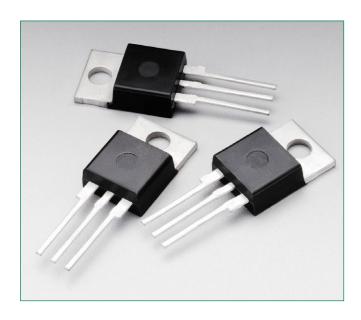


MAC16CMG, MAC16CNG





Description

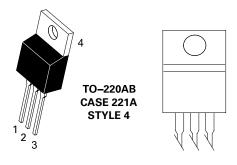
Designed primarily for full wave ac control applications, such as motor controls, heating controls or dimmers; or wherever full—wave, silicon gate—controlled devices are needed.

Features

- High Commutating di/dt and High Immunity to dV/dt @ 125°C
- Minimizes Snubber Networks for Protection
- Blocking Voltage to 800 Volts
- On-State Current Rating of 16 Amperes RMS
- High Surge Current Capability – 150 Amperes
- Industry Standard TO-220 Package for Ease of Design

- Glass Passivated Junctions for Reliability and Uniformity
- Operational in Three Quadrants, Q1, Q2, and Q3
- These Devices are Pb-Free and are RoHS Compliant
- These Devices are Pb-Free and are RoHS Compliant

Pin Out



Functional Diagram



Additional Information







Resources



Samples



Maximum Ratings (T_J = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Peak Repetitive Off-State Voltage (Note 1) (- 40 to 125°C, Sine Wave, 50 to 60 Hz, Gate Open) AC1 MAC	CM V _{DRM} ,	600 800	V
On-State RMS Current (Full Cycle Sine Wave, 50 to 60 Hz, T _c = 80°C)	I _{T (RMS)}	16	А
Peak Non-Repetitive Surge Current (One Full Cycle Sine Wave, 60 Hz, T_c = 125°C)	I _{TSM}	150	А
Circuit Fusing Consideration (t = 8.3 ms)	l²t	93	A²sec
Peak Gate Power ($T_C = +80^{\circ}C$, Pulse Width = 1.0 μ s)	P _{GM}	20	W
Average Gate Power (t = 8.3 ms, $T_c = 80$ °C)	P _{G(AV)}	0.5	W
Operating Junction Temperature Range	T _J	-40 to +125	°C
Storage Temperature Range	T _{stg}	-40 to +125	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied.

Thermal Characteristics

Rating	Symbol	Value	Unit	
Thermal Resistance,	Junction-to-Case (AC) Junction-to-Ambient	R _{ejc} R _{eja}	2.2 62.5	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds		T_{L}	260	°C

Electrical Characteristics - OFF (T, = 25°C unless otherwise noted; Electricals apply in both directions)

Characteristic		Symbol	Min	Тур	Max	Unit
Peak Repetitive Blocking Current	T, = 25°C	I _{DRM} ,	-	-	0.01	A
$(V_D = V_{DRM} = V_{RRM}, Gate Open)$	T _J = 125°C	I _{RRM}	-	-	2.0	mA

Electrical Characteristics - ON (T₁ = 25°C unless otherwise noted; Electricals apply in both directions)

Characteristic		Symbol	Min	Тур	Max	Unit
Peak On-State Voltage (Note 2) (I _{TM} = ±21 A Peak)		V _{TM}	-	1.2	1.6	V
Gate Trigger Current	MT2(+), G(+)		8.0	12	35	
(Continuous dc)	MT2(+), G(-)	I _{GT}	8.0	16	35	mA
$(V_{D} = 12 \text{ V}, R_{L} = 100 \Omega)$	MT2(-), G(-)		8.0	20	35	
Gate Trigger Voltage (Continuous dc)	MT2(+), G(+)	V _{GT}	0.5	0.75	1.5	
	MT2(+), G(-)		V _{GT}	0.5	0.72	1.5
$(V_{D} = 12 \text{ V}, R_{L} = 100 \Omega)$	MT2(-), G(-)			0.5	0.82	1.5
	MT2(+), G(+)	V _{GD}	-	25	50	
Latching Current $(V_D = 24 \text{ V, } I_G = 35 \text{ mA})$	MT2(+), G(-)		-	40	80	V
	MT2(-), G(-)		-	24	50	
Holding Current (V _D = 12 V _{dc} , Gate Open, Initiating Current = ±200 mA))		I _H	-	20	40	mA

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions

2. Indicates Pulse Test: Pulse Width \leq 2.0 ms, Duty Cycle \leq 2%.

Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. V_{DRM} and V_{RRM} for all types can be applied on a continuous basis. Ratings apply for zero or negative gate voltage; however, positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the devices are exceeded.



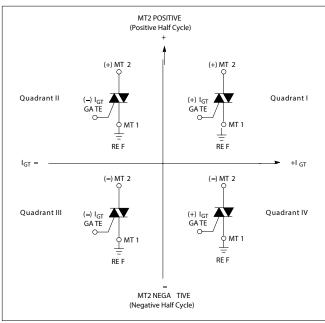
Dynamic Characteristics

Characteristic		Min	Тур	Max	Unit
Rate of Change of Commutating Current ($V_D = 400 \text{ V}$, $I_{TM} = 6.0 \text{ A}$, Commutating dV/dt = 24 V/ μ s, Gate Open, $I_J = 125^{\circ}$ C, $I_J = 125^{\circ}$	(di/dt)c	15	_	_	A/ms
Critical Rate of Rise of Off-State Voltage $(V_D = Rated V_{DRM}, Exponential Waveform, Gate Open, T_J = 125°C)$		600	_	_	V/µs
Repetitive Critical Rate of Rise of On-State Current IPK = 50 A; PW = 40 µsec; diG/dt = 200 mA/µsec; f = 60 Hz		_	_	10	

Voltage Current Characteristic of SCR

Symbol	Parameter	
V_{DRM}	Peak Repetitive Forward Off State Voltage	
I _{DRM}	Peak Forward Blocking Current	
V_{RRM}	Peak Repetitive Reverse Off State Voltage	
IRRM	Peak Reverse Blocking Current	
V _{TM}	Maximum On State Voltage	
I	Holding Current	

Quadrant Definitions for a Triac



All polarities are referenced to MT1. With in–phase signals (using standard AC lines) quadrants I and III are used

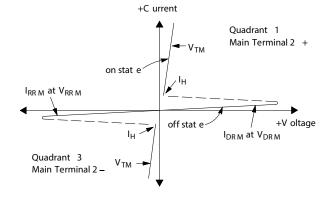




Figure 1. Typical Gate Trigger Current vs Junction Temperature

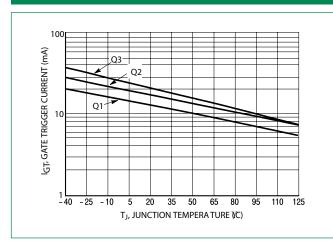


Figure 2. Typical Gate Trigger Voltage vs Junction Temperature

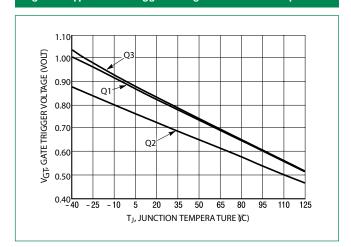


Figure 3. Typical Holding Current vs Junction Temperature

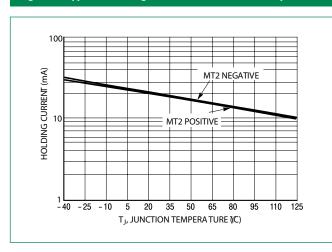


Figure 4. Typical Latching Current vs Junction Temperature

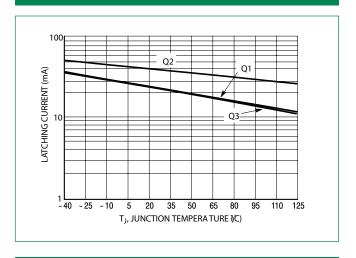


Figure 5. Typical RMS Current Derating

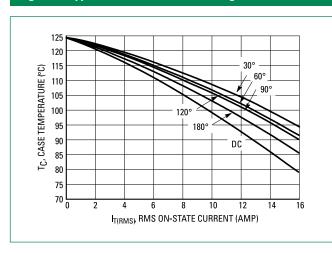


Figure 6. On-State Power Dissipation

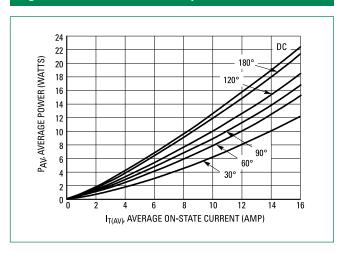




Figure 7. On-State Characteristics

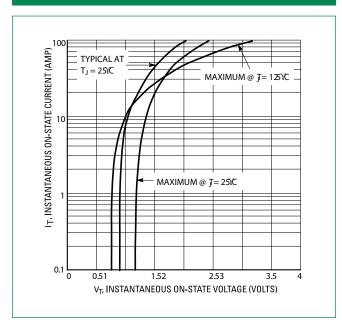
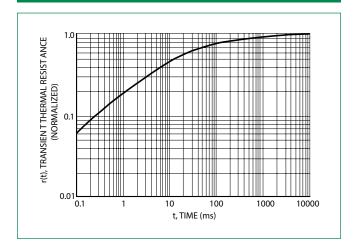


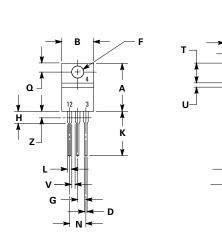
Figure 8. Typical Thermal Response



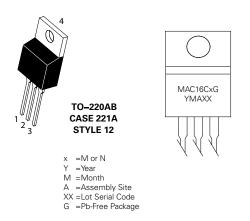
-T- SEATING PLANE



Dimensions



Part Marking System



	Inc	hes	Millimeters		
Dim	Min	Max	Min	Max	
Α	0.590	0.620	14.99	15.75	
В	0.380	0.420	9.65	10.67	
С	0.178	0.188	4.52	4.78	
D	0.025	0.035	0.64	0.89	
F	0.142	0.147	3.61	3.73	
G	0.095	0.105	2.41	2.67	
Н	0.110	0.130	2.79	3.30	
J	0.018	0.024	0.46	0.61	
K	0.540	0.575	13.72	14.61	
L	0.060	0.075	1.52	1.91	
N	0.195	0.205	4.95	5.21	
Q	0.105	0.115	2.67	2.92	
R	0.085	0.095	2.16	2.41	
S	0.045	0.060	1.14	1.52	
Т	0.235	0.255	5.97	6.47	
U	0.000	0.050	0.00	1.27	
V	0.045		1.15		
Z		0.080		2.04	

2	Main Terminal 2			
3	Gate			
4	No Connection			
Ordering Information				

Pin Assignment

Main Terminal 1

Device	Package	Shipping
MAC16CMG	TO-220AB	500 Units / Rail
MAC16CNG	(Pb-Free)	500 Offics / Hall

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- 2. CONTROLLING DIMENSION: INCH.
- DIMENSION Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE ALLOWED.